

Results of Expressline II TEC Modules and ARC Status

Torsten Franke

Markus Axer, Franz Beißel, Günther Flügge, Stefan Kasselmann,
Joachim Mnich, Andreas Nowack, Oliver Pooth, Reiner Schulte

III. Physikalisches Institut B

RWTH Aachen

- TEC Ring 6 Expressline II
 - Various Tests
 - Test with LEDs
 - Automated Pinhole Test
 - Result Table
- Some Comments on the new Frontend

The background of the slide is a faded, repeating pattern of detector modules, likely calorimeters, arranged in a grid. Each module is rectangular with a central square area and various electronic components on top.

Expressline II Tests

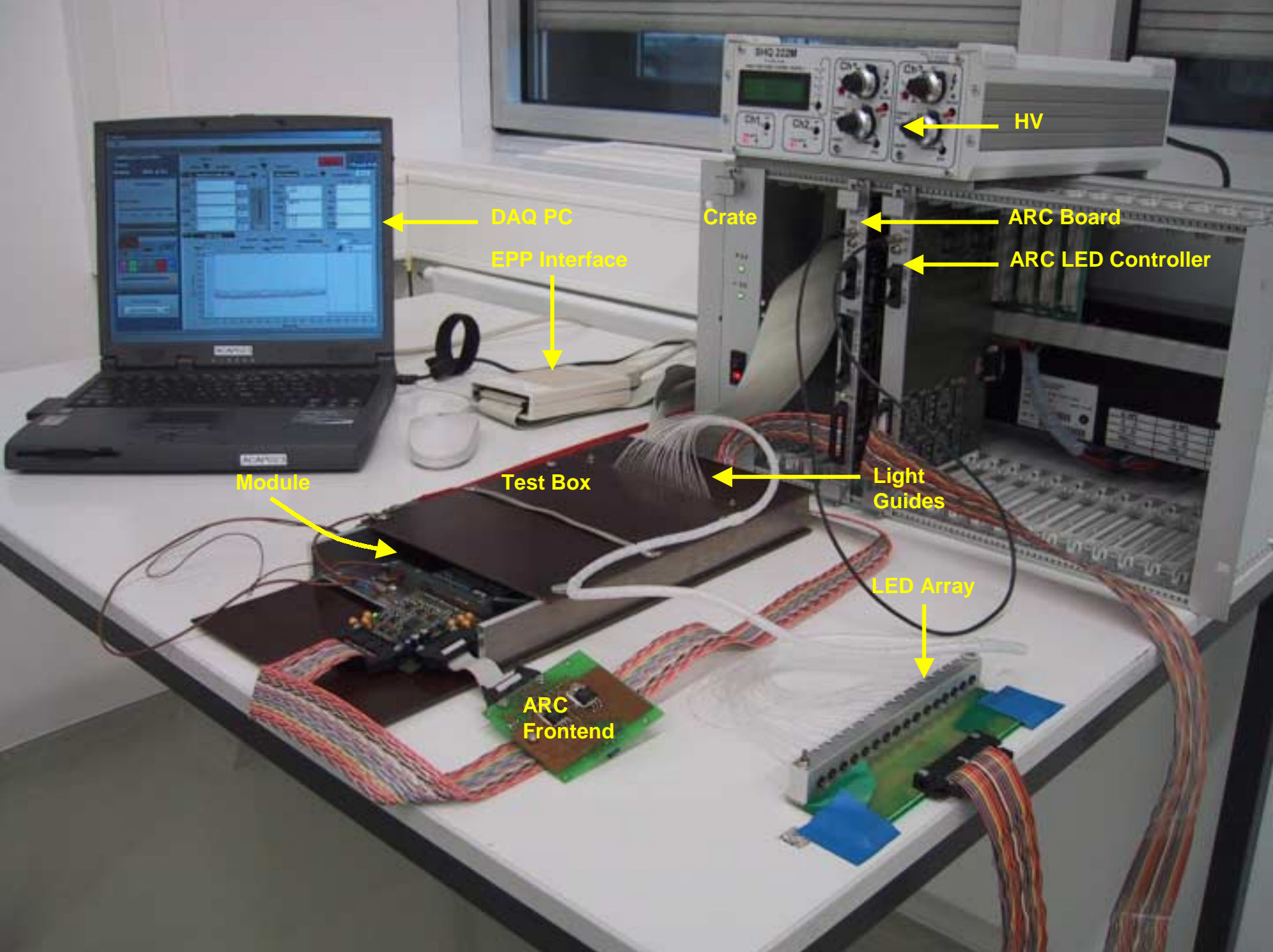
- 9 Modules
 - TEC Ring 6
 - Equipped with ceramic hybrids
 - Assembled on the gantry in Bruxelles
 - Bonded in Aachen (AC I)
- Tests done by Aachen I (*Jan Olzem, Katja Klein*)
 - Using ARC & ARC LED System

- Expressline Tests consisted of

- I²C Test
- Pedestal & Noise Test
- Common Mode Test
- Pulse Shape Test
- Pipeline Test
- IV Test
- LED Tests
 - With Pulsed Light
 - With Continuous Light ⇒ Pinhole Test



In the same clean room where the bonding was done



HV

DAQ PC

Crate

ARC Board

EPP Interface

ARC LED Controller

Module

Test Box

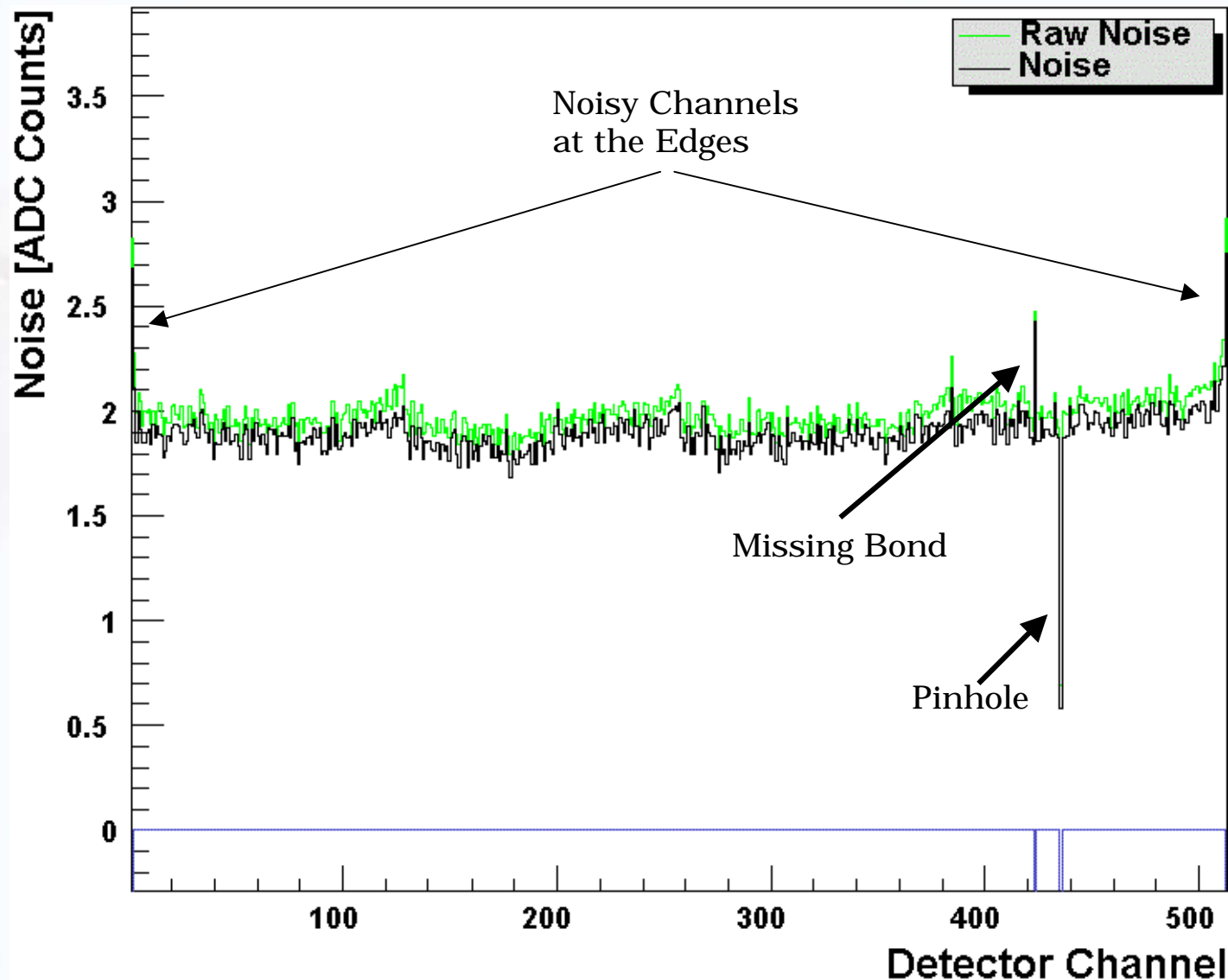
Light Guides

LED Array

ARC Frontend

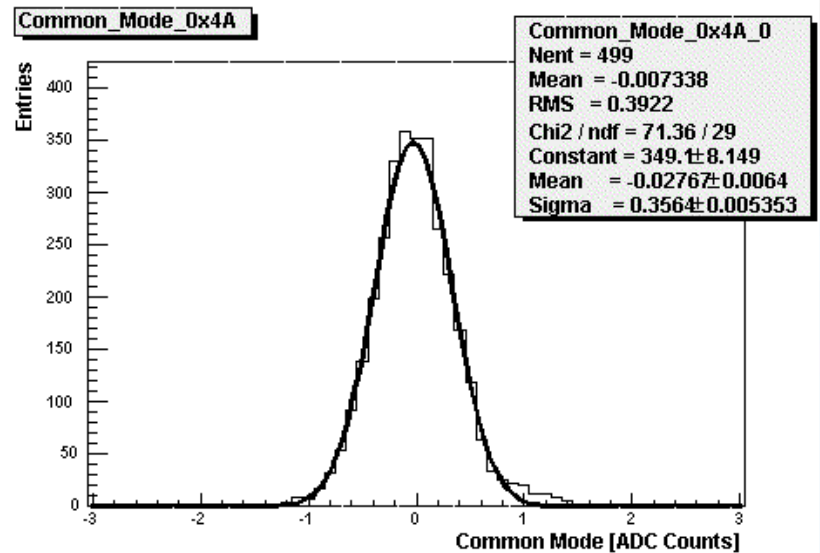
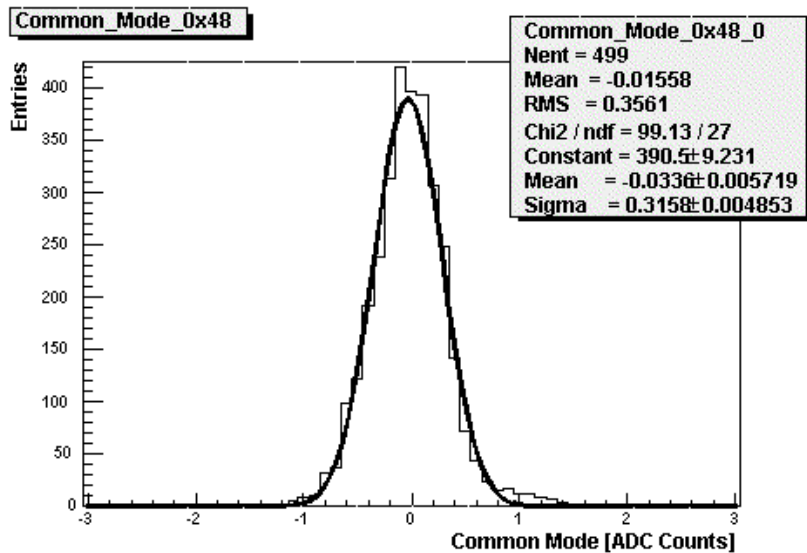
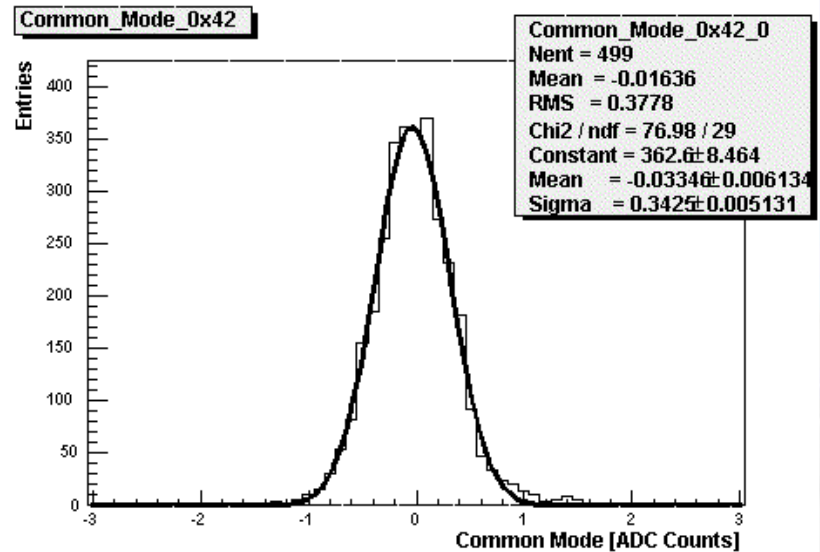
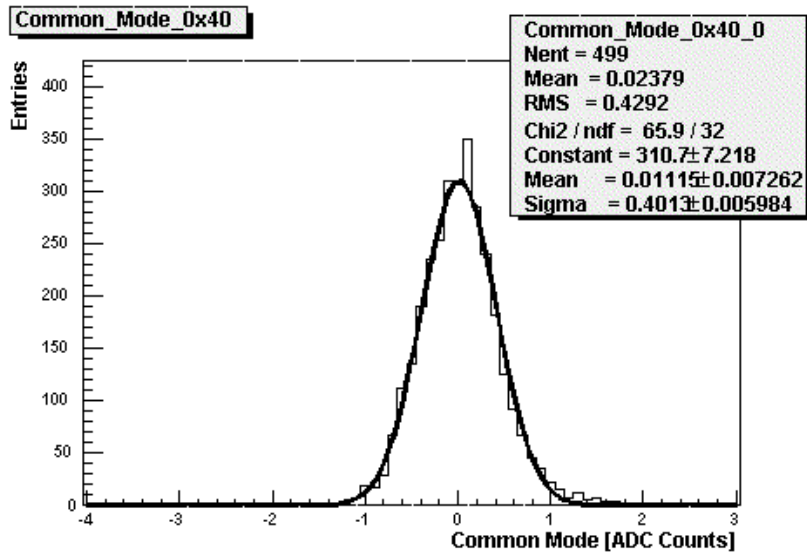
The background of the slide is a faded, repeating pattern of detector modules, likely calorimeters, arranged in a grid. Each module is rectangular with a central square area and various electronic components on top.

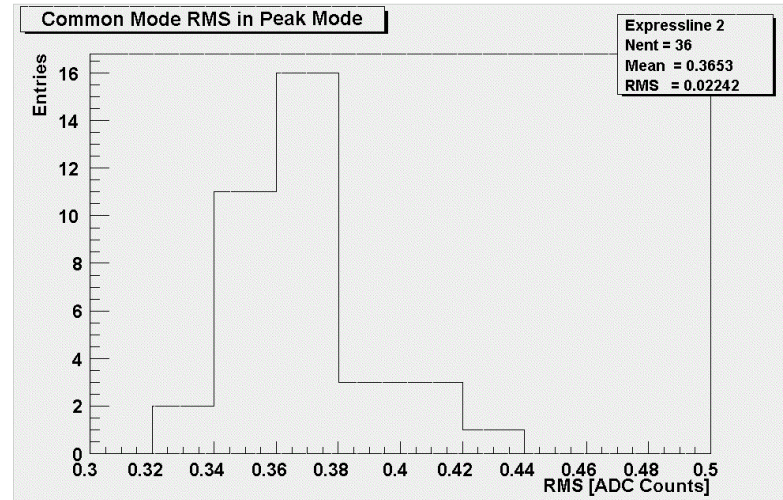
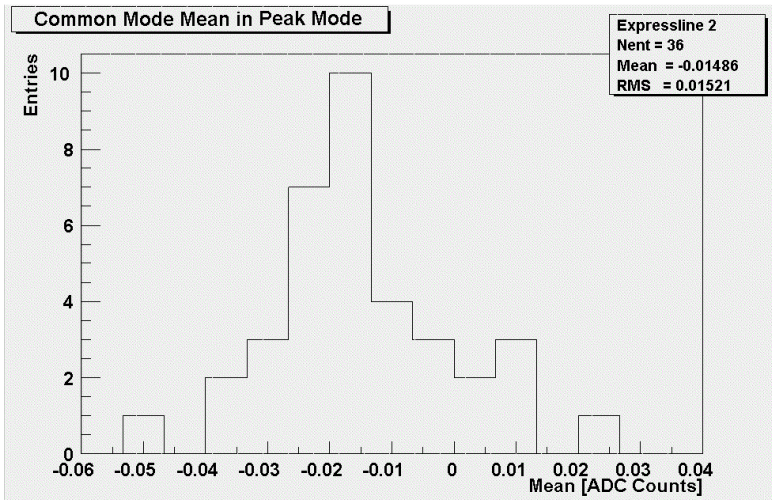
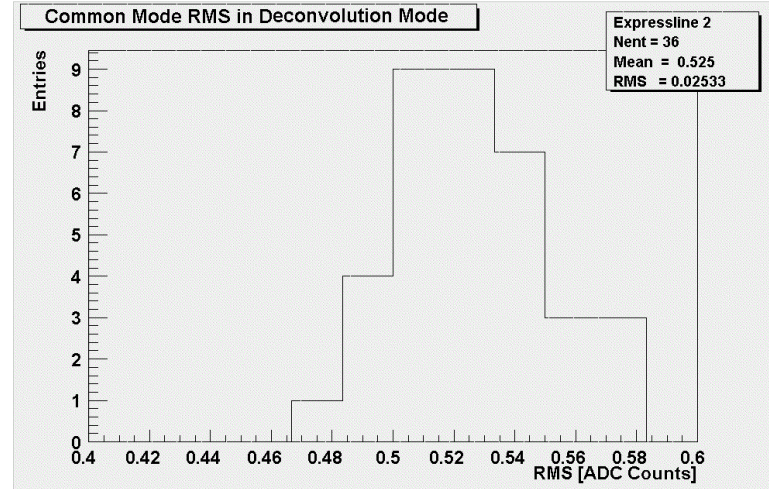
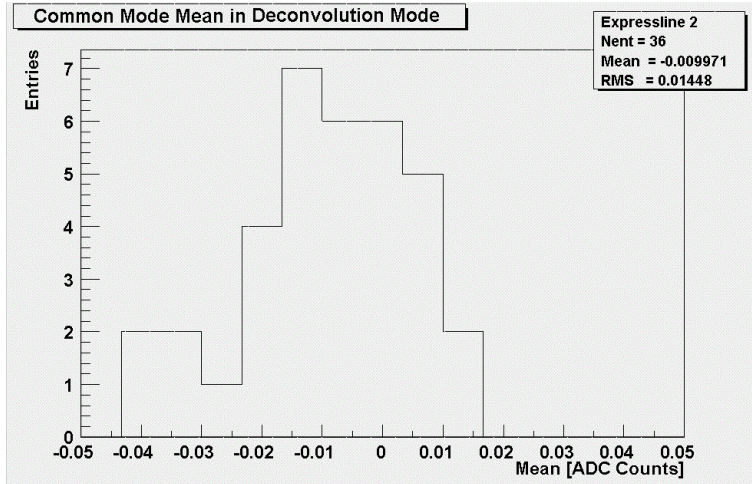
Noise Test



The background of the slide is a faded, repeating pattern of detector modules, likely calorimeters, arranged in a grid. Each module is rectangular with a central square area and various electronic components on top.

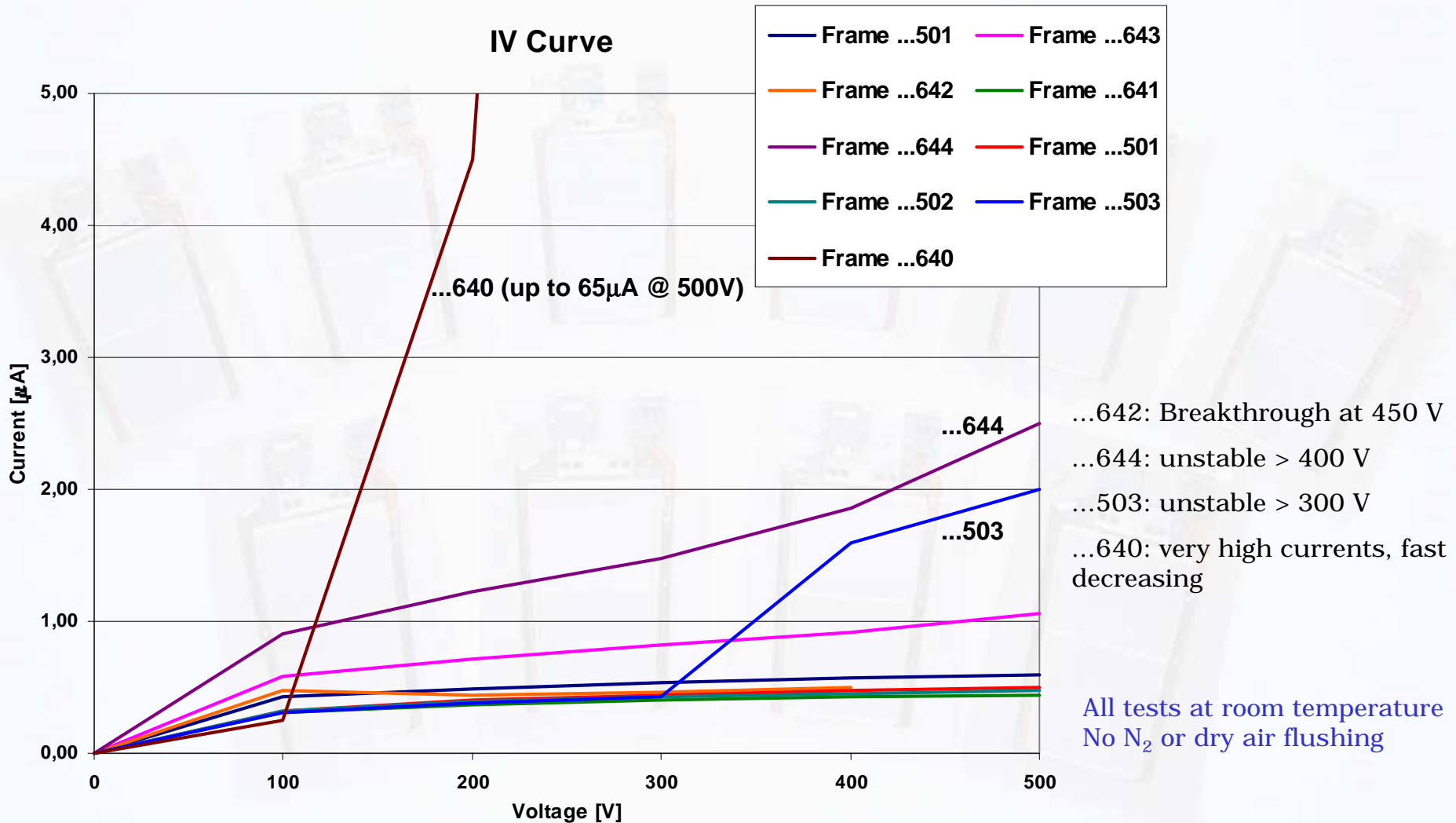
Common Mode Test






The background of the slide is a faded, repeating pattern of silicon detector modules. Each module is a rectangular component with a central square area and various electrical connections at the top and bottom.

IV-Test



The background of the slide is a faded, repeating pattern of rectangular test strips. Each strip contains several small, square components, likely LEDs, arranged in a grid. The strips are oriented vertically and slightly offset from each other, creating a sense of depth and repetition.

Tests with LEDs

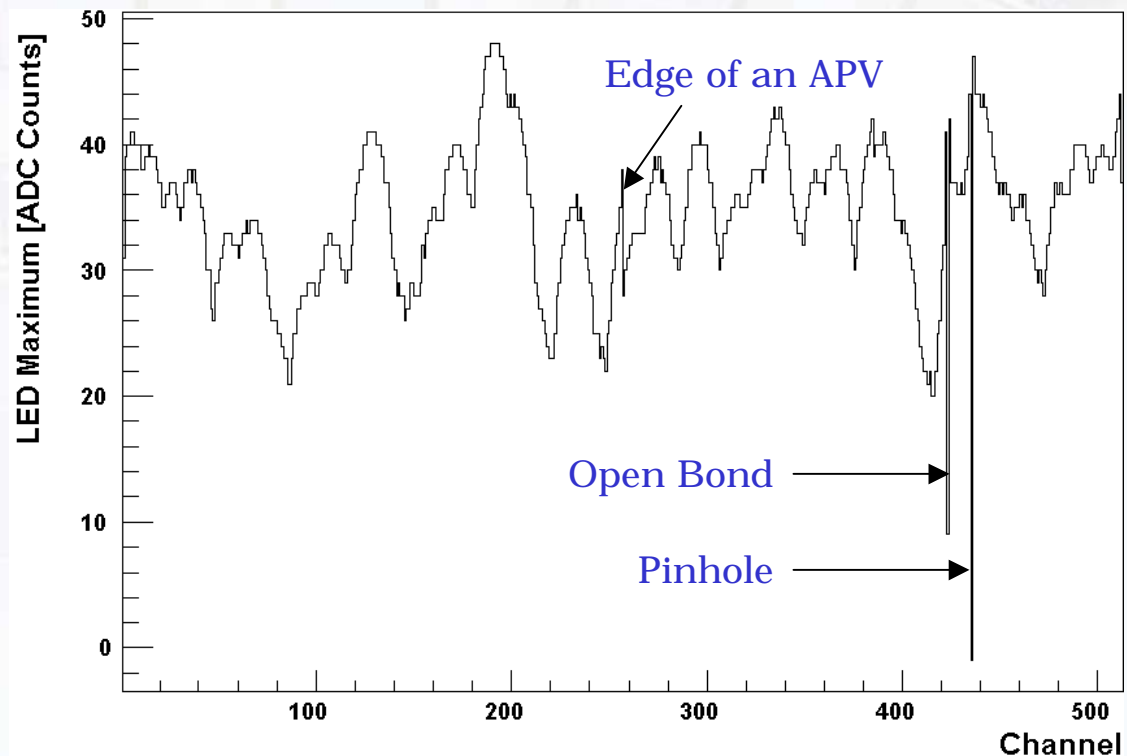
The background of the slide is a faded, repeating pattern of several rectangular LED chips. Each chip is mounted on a small metal carrier and has a white, square light-emitting area in the center. The chips are arranged in a grid-like pattern, slightly offset from each other.


LED Tests with Pulsed Light

● Applying pulsed light to the sensors

- At low pulse rates
 - With short pulse length and medium intensity
 - Switching the LEDs one by one
- ⇒ To avoid saturation effects of the APVs

- Intensity varying strongly
- But defects are clearly visible
- Problem to apply cuts



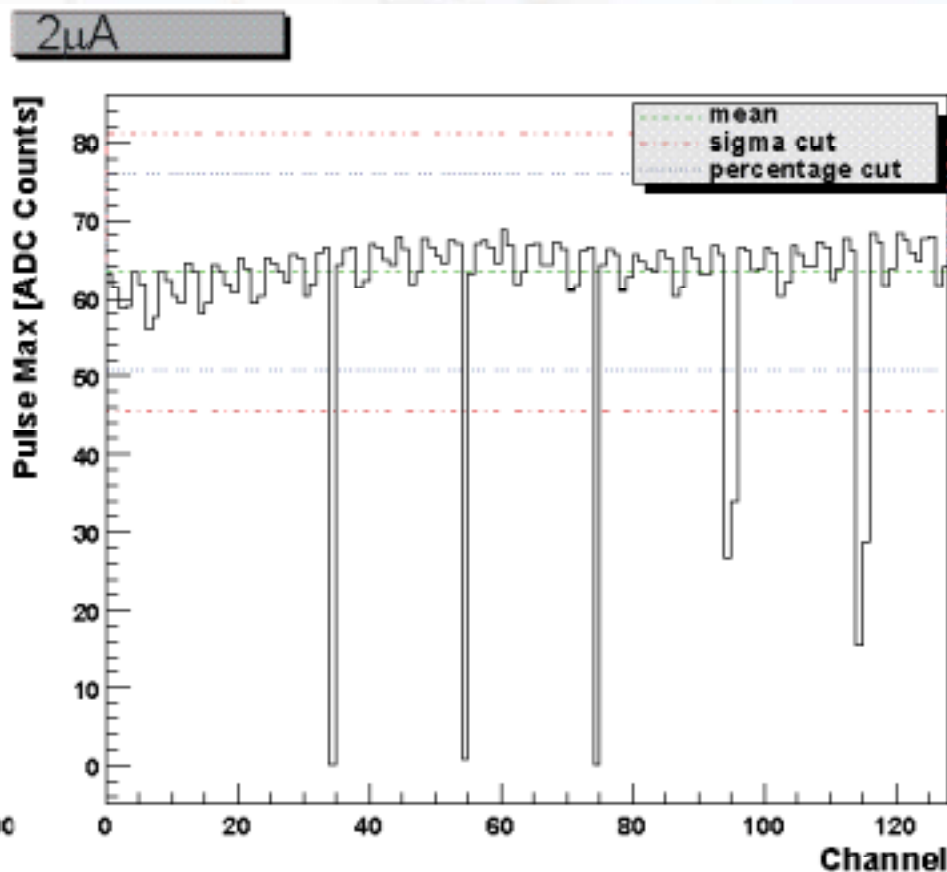
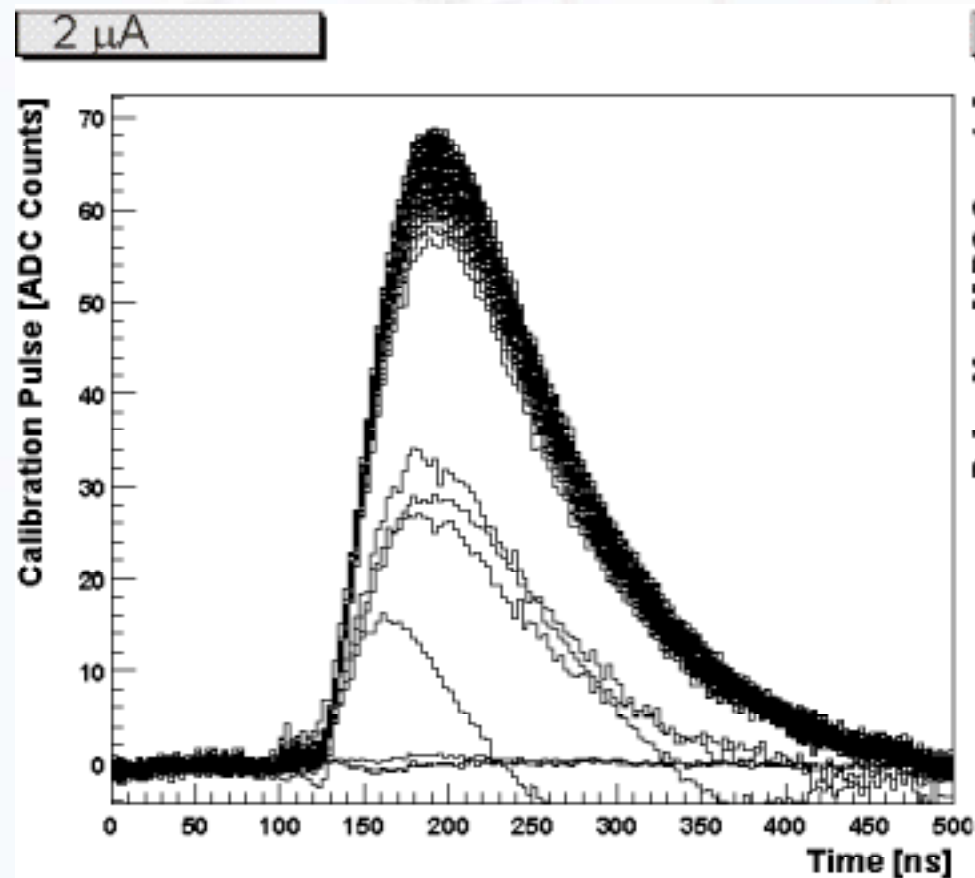
The background of the slide is a faded, repeating pattern of LED chips. Each chip is rectangular with a central square area and several small components at the top and bottom edges.

LED Tests

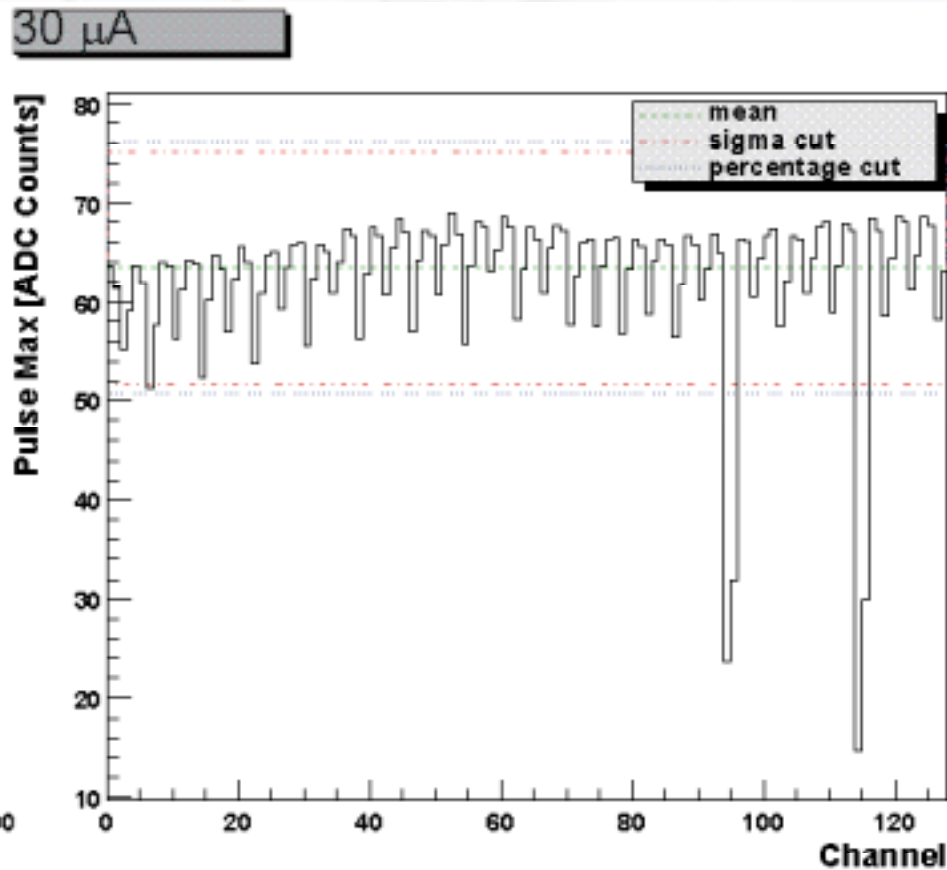
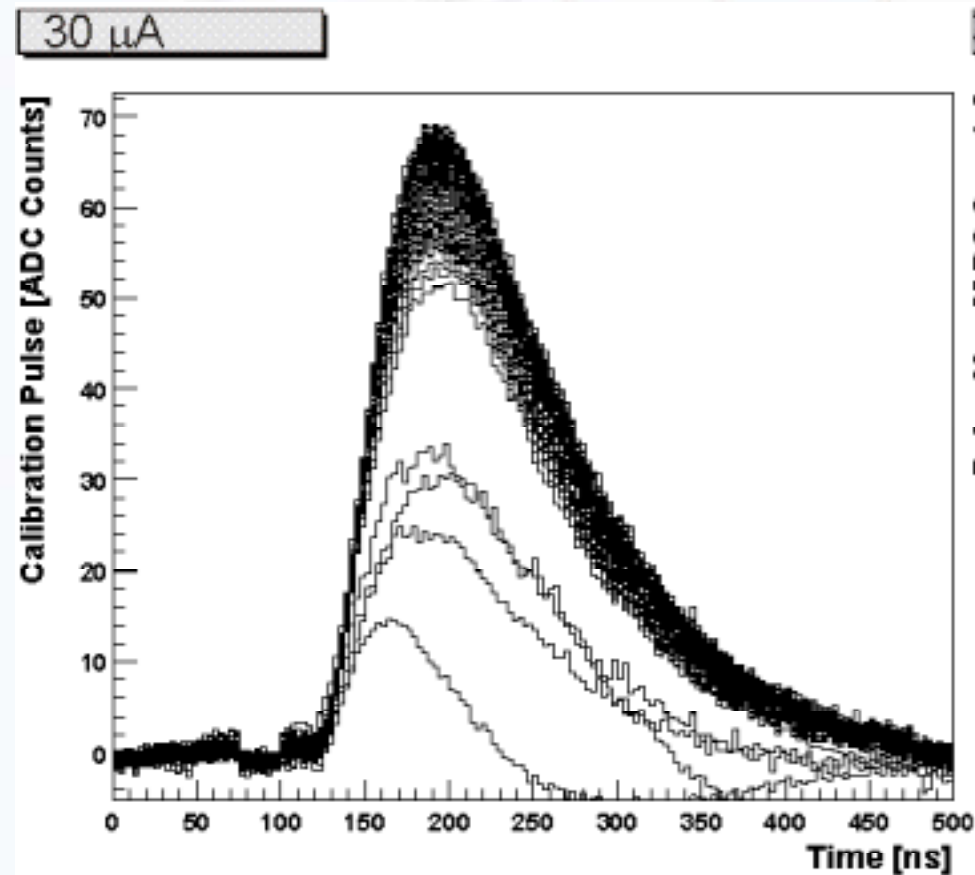
with Continuous Light

Pinhole Tests

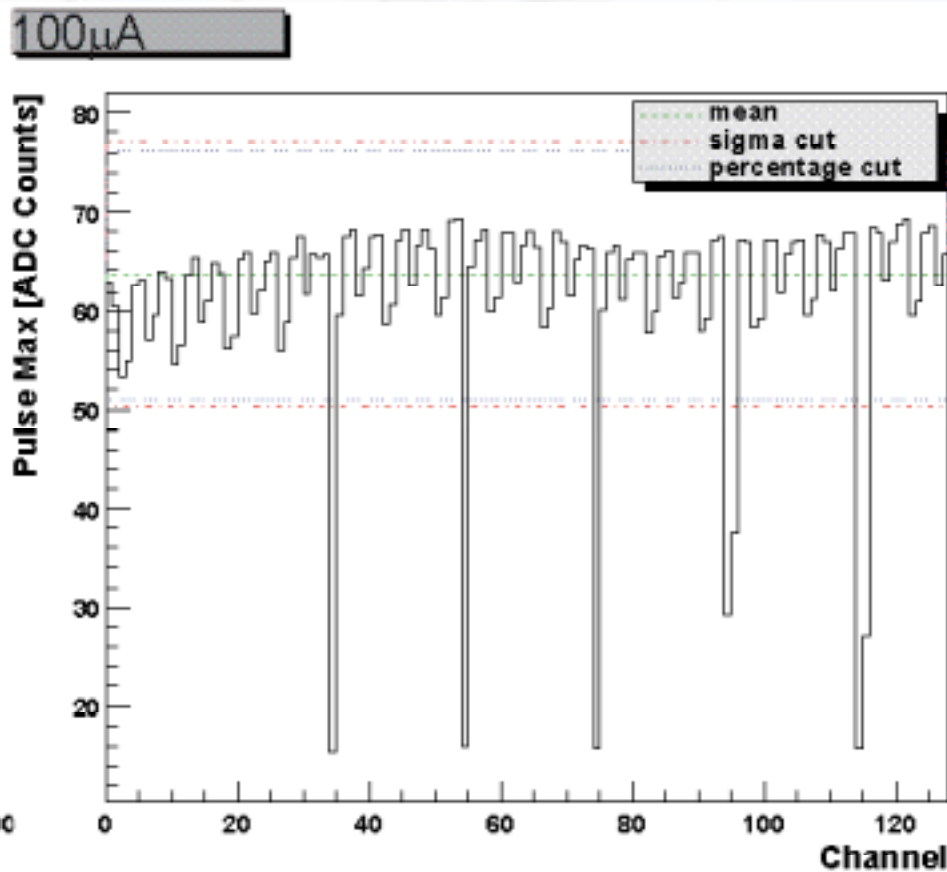
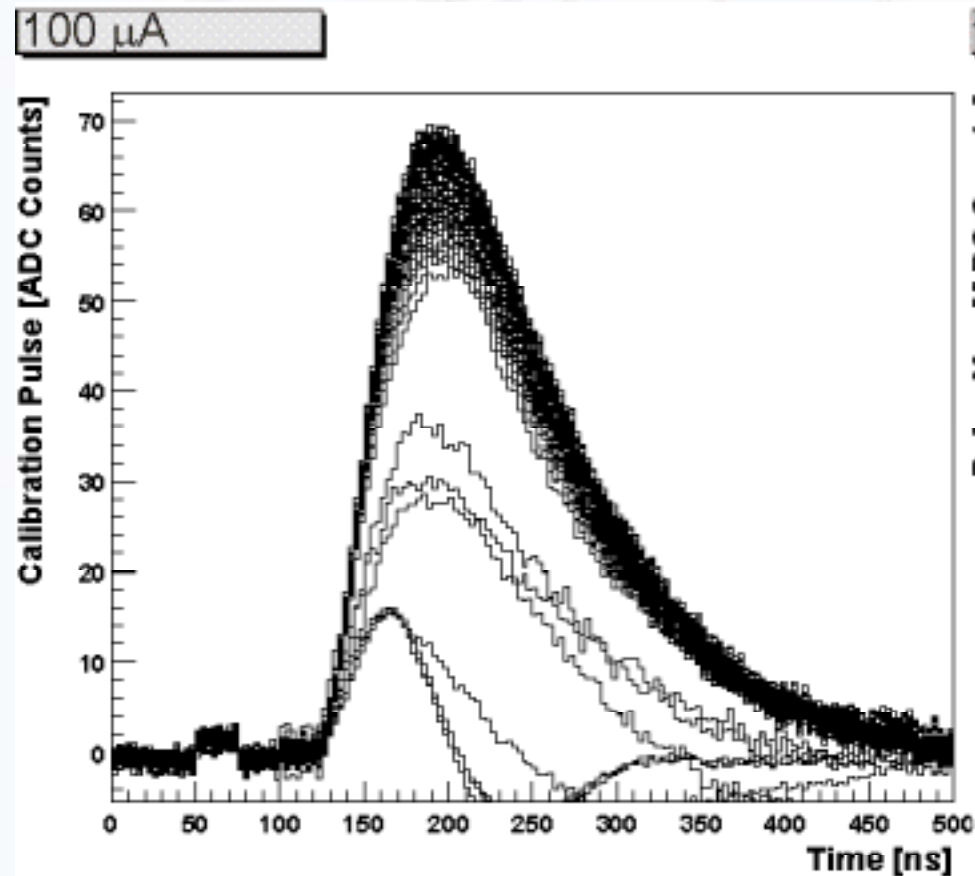
- Applying constant light of various intensities to the sensors
- Measure the height of calibration pulses at the maximum for each of the LED intensities



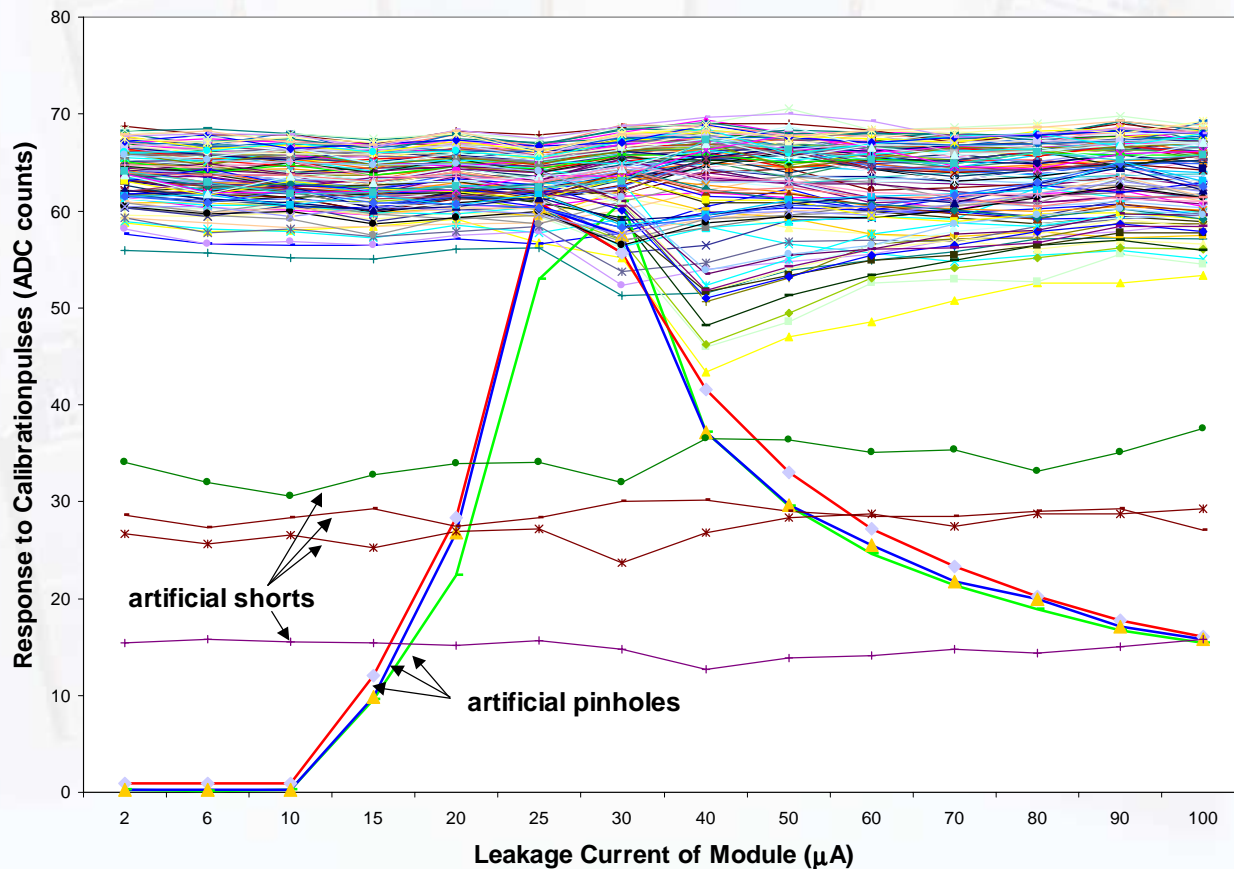
- Applying constant light of various intensities to the sensors
- Measure the height of calibration pulses at the maximum for each of the LED intensities

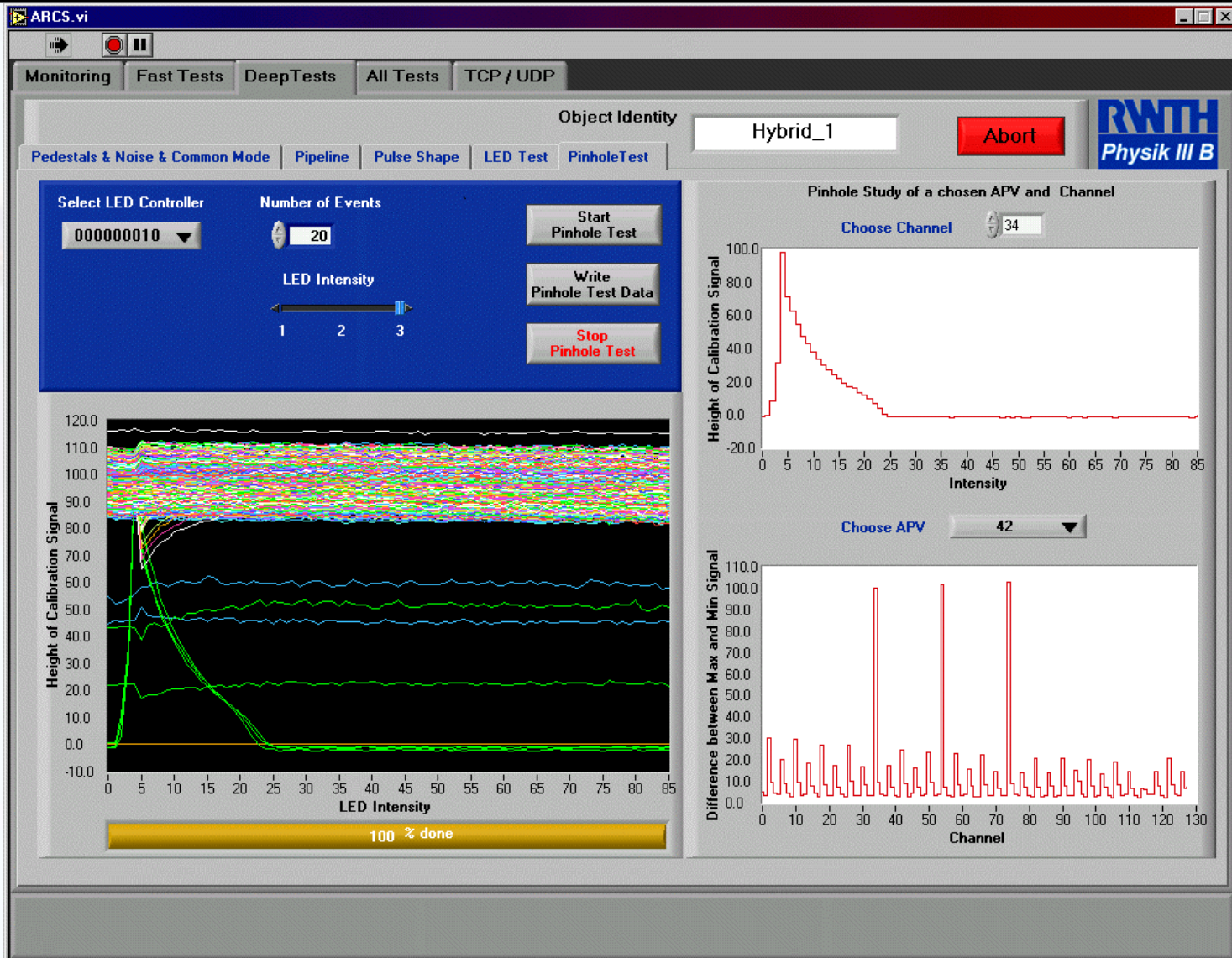


- Applying constant light of various intensities to the sensors
- Measure the height of calibration pulses at the maximum for each of the LED intensities



- Applying constant light of various intensities to the sensors
- Measure the height of calibration pulses at the maximum for each of the LED intensities





Result Table

Frame 30200020000- xxx	Hybrid 30216630200- xxx	Channel (draft numbering)	Channel (sensor numbering)	Noise (Inverter on)				Pulse Shape (Inverter on)						LED Test		Pinhole-test suspicious	Visual Inspection or (assumed) Error		
				Peak		Dec		Peak			Dec			signal					
				higher	lower	higher	lower	rise time	peak time	signal height	rise time	peak time	signal height	higher	lower			higher	lower
				shorter	longer	shorter	longer	shorter	longer	shorter	longer	shorter	longer	shorter	longer			shorter	longer
..501	..106	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
..502	..105	495	18	-	-	-	x	x	(x)	(x)	x	x	-	x	-	-	-	missing bond (SEN-SEN)	
..503	..102	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
..640	..098	435	78	x	x	(x)	(x)	0	(x)	(x)	0	x	x	x	x	x	x	pinhole	
		423	90	-	x	x	x	x	x	x	x	x	x	x	-	-	missing bond (APV-PA)		
..641	..099	270	243	x	x	x	x	x	x	x	x	x	x	-	-	-	broken line on pitch adapter ?		
..642	..097	183	330	-	-	-	-	-	-	-	-	-	-	-	x	x	high leakage current pinhole		
		512	1	(x)	(x)	-	-	-	-	-	-	-	-	-	x	x	high leakage current pinhole		
..643	..101	65	448	x	x	x	x	0	x	x	0	x	x	x	x	x	pinhole		
		3	510	x	x	x	x	0	x	x	0	x	x	x	x	x	pinhole		
..644	..104	155	358	x	x	(x)	(x)	0	(x)	(x)	0	x	x	(x)	(x)	(x)	high leakage current pinhole		
..645	..100	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-

Only three bonding errors, but 6 pinholes

- Still noise on the edges of the sensors
- Noise at the edges between two APVs became better
- How dangerous are these “high leakage current pinholes” ?
- Have these pinholes been caused by the bonding ?
- Does the test affect the sensors ?

- Is intended to facilitate the use of ARC in module tests
 - Good grounding is a system independent problem

- The new ARC Frontend is **not** a new development
 - Is based on the previous one
 - Analogue part identical
 - But some additions:
 - Backplane pulse
 - External thermistor
 - Humidity sensor (optional)
 - HV

- Status:
 - PCBs received
 - 1 assembled and actually tested

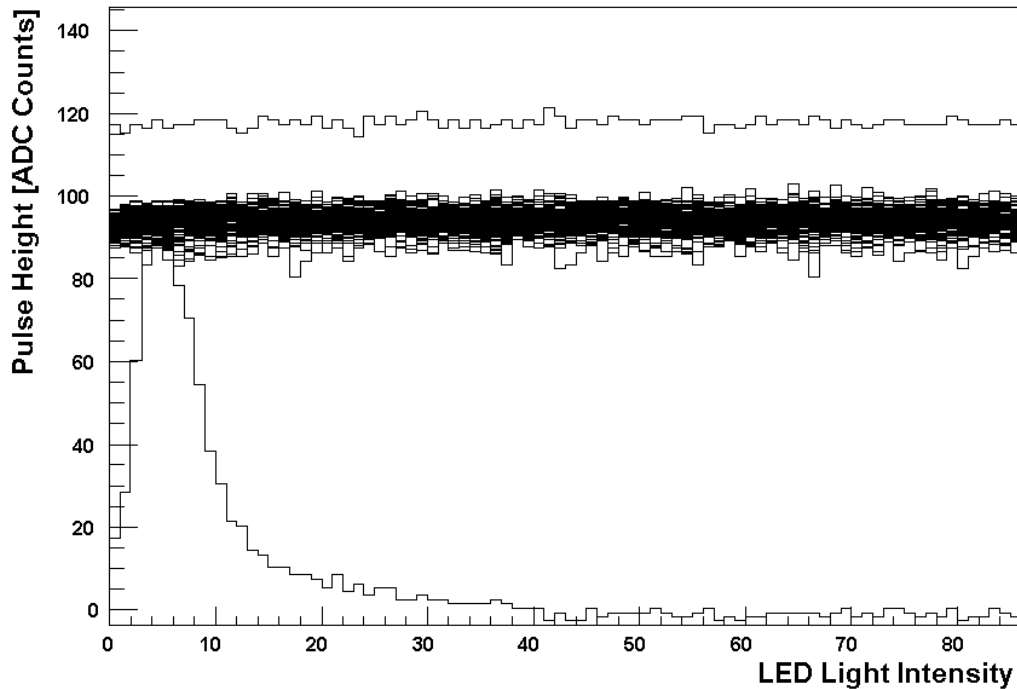


The background of the slide is a light, faded image of several CMS calorimeter modules, which are large, rectangular, multi-layered detectors used for measuring the energy of particles.

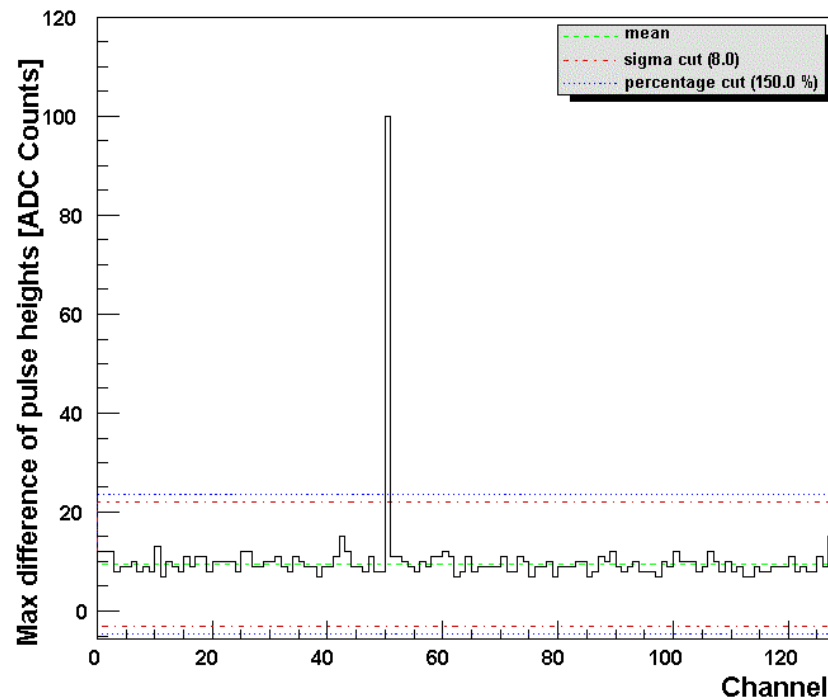
End

...and Merry Christmas

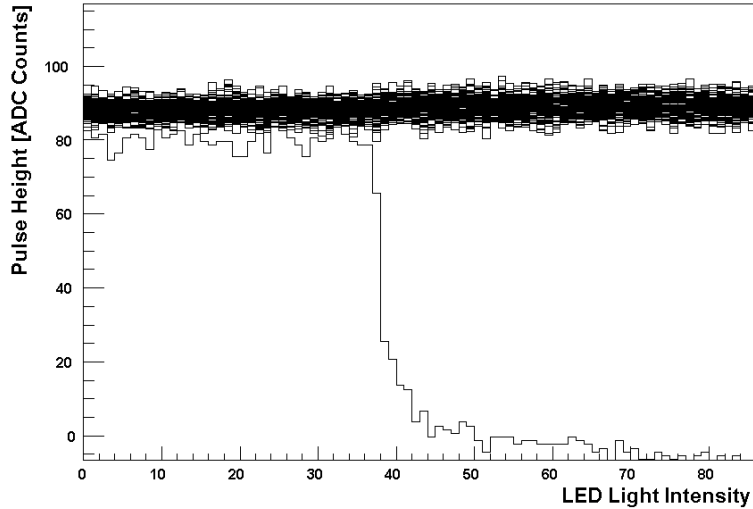
APV 0x4A : calibration pulse height vs. LED light intensity



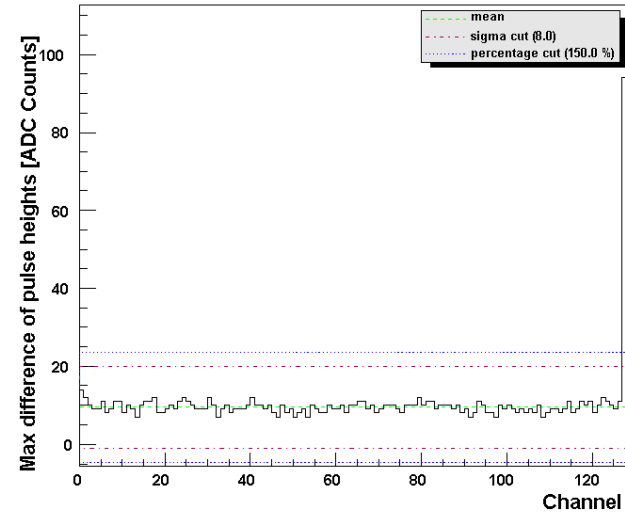
APV 0x4A



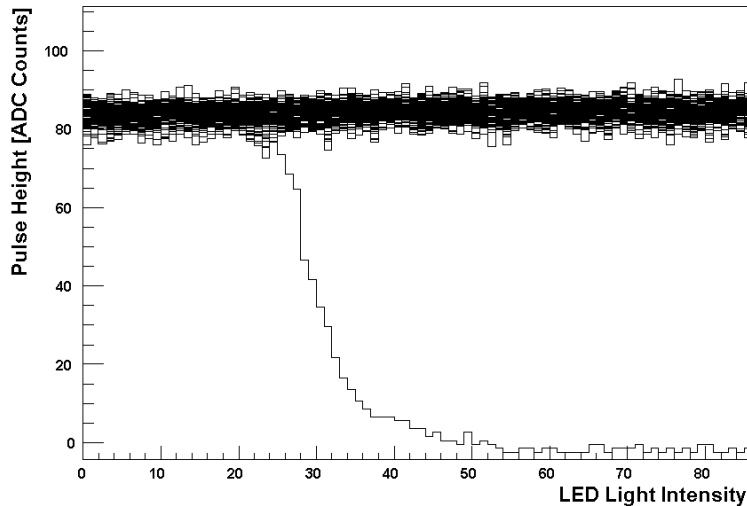
APV 0x4A : calibration pulse height vs. LED light intensity



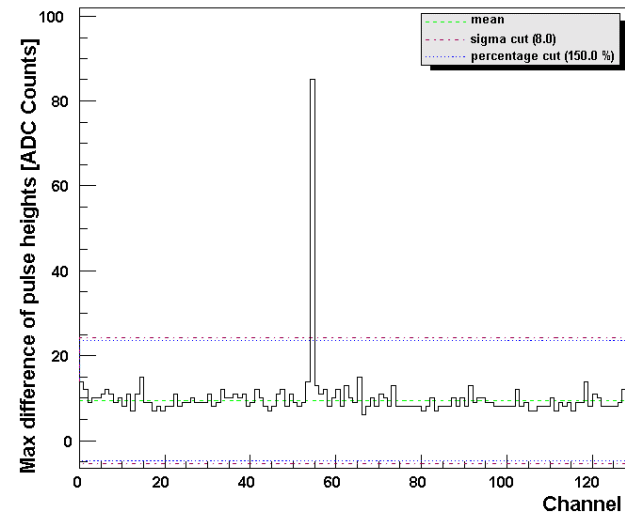
APV 0x4A



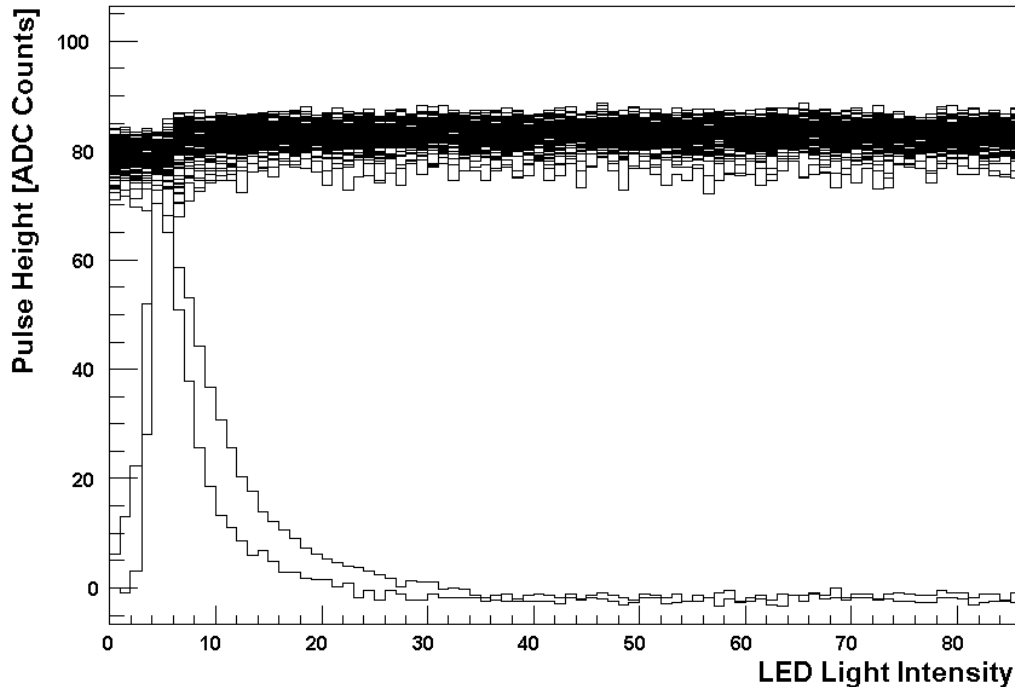
APV 0x42 : calibration pulse height vs. LED light intensity



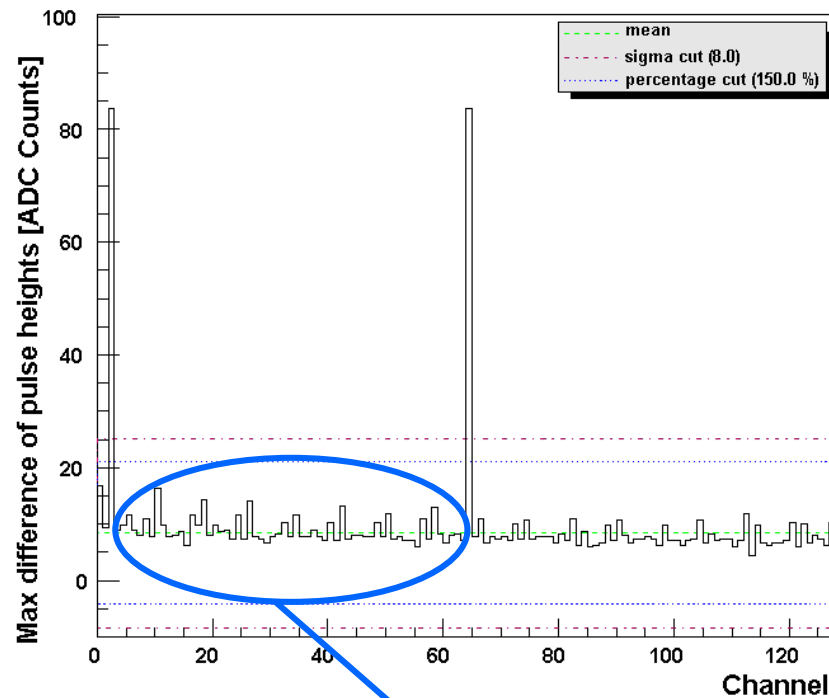
APV 0x42



APV 0x40 : calibration pulse height vs. LED light intensity

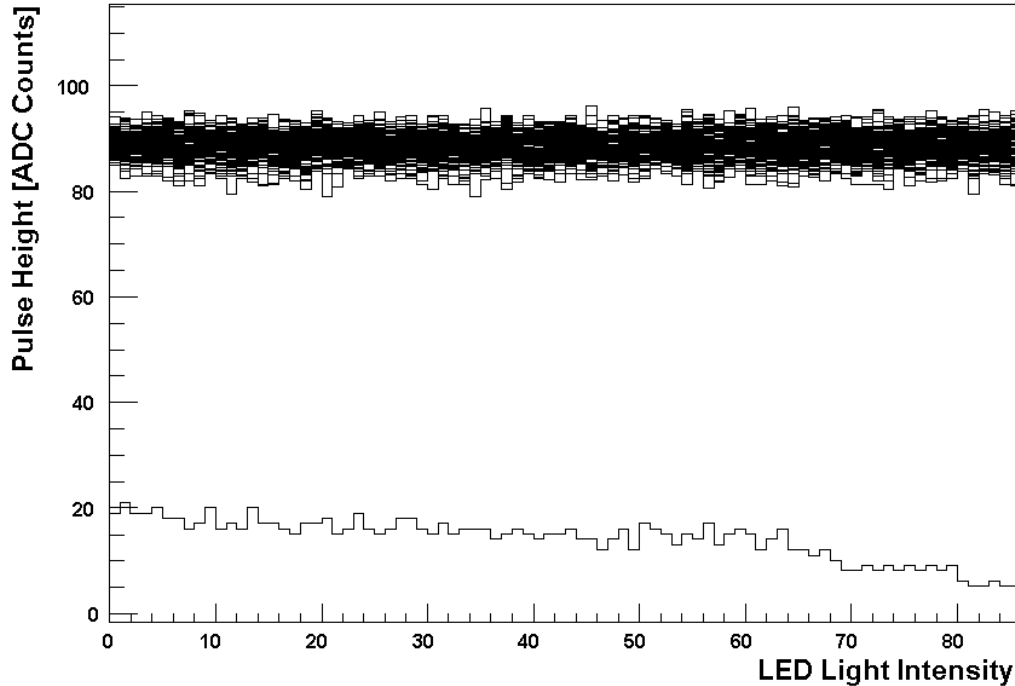


APV 0x40

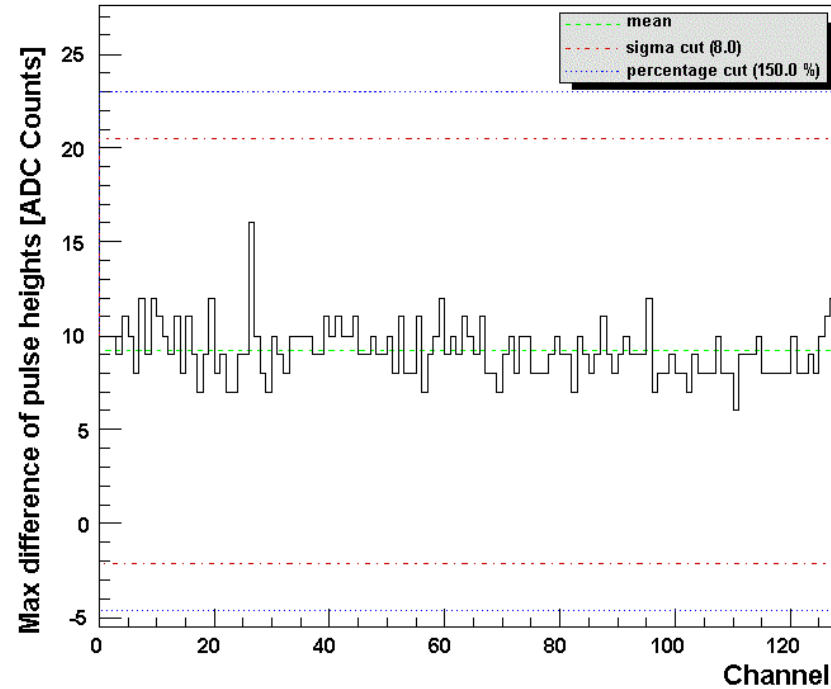


Calibration group neighbours are affected by these pinholes (as for the artificial pinholes)

APV 0x42 : calibration pulse height vs. LED light intensity



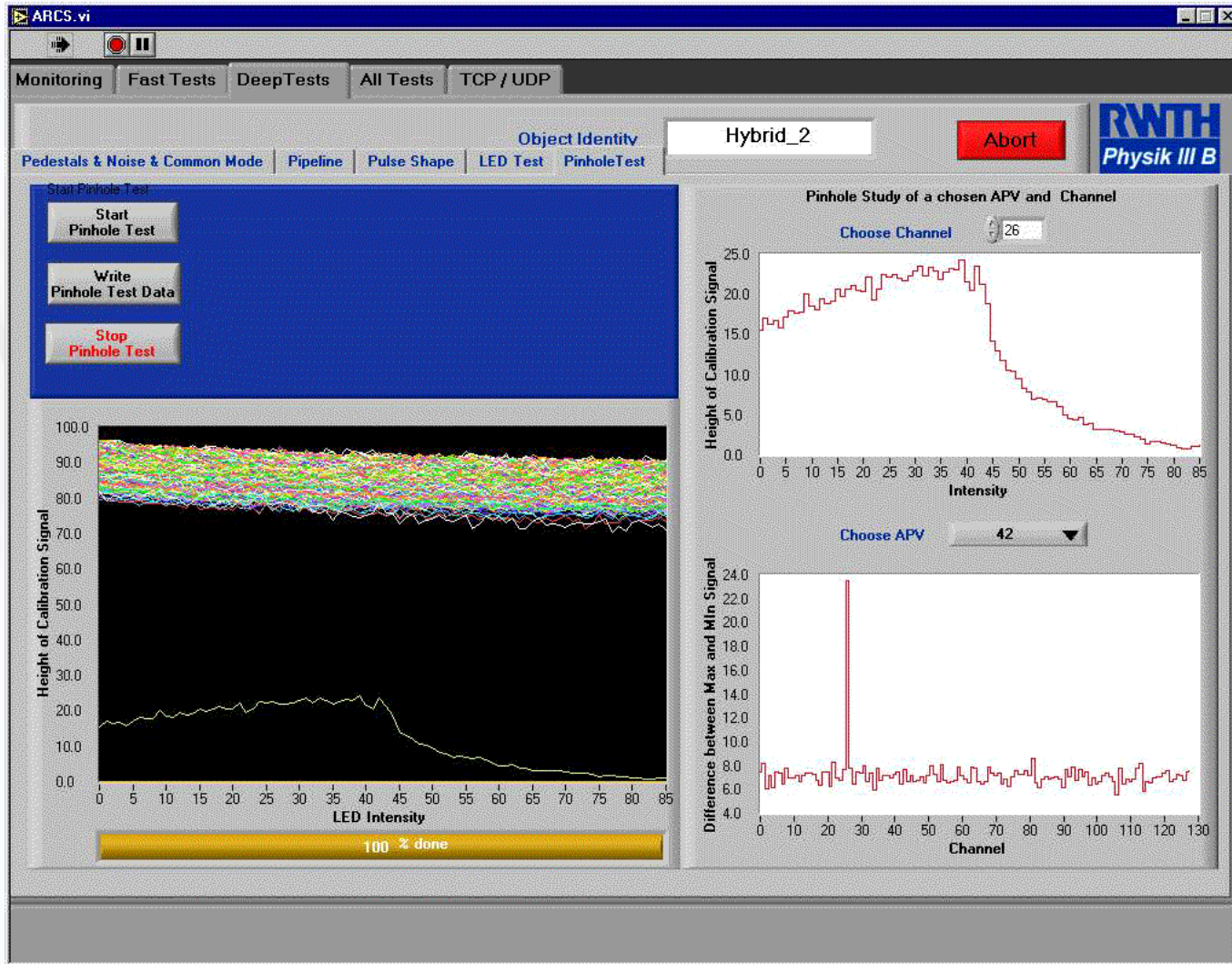
APV 0x42



This Pinhole started to behave like a high Leakage current pinhole after several test runs



Behaviour of a High Leakage Current Pinhole during several Repetitions of the test



First trialversion of the pinhole test

Leakage Current vs. LED Intensity

